

## Digital SD Card Features both SLC and MLC Flash Architectures



The Netherlands, 11th July 2011- Apacer is launching a new industrial SD card designed for embedded systems in harsh storage environments. The new industrial SD card features high reliability, high storage and resistance to extended temperatures. Because of these advantages the card can be widely used in industrial applications, military, communication, surveillance, medical devices and car navigation, satisfying the storage need of demanding industrial enterprises.

Compliant with Ver. 2.0 standard and SDHC Class 10 high-speed transmission standard (as defined by the SD Association), the new SD card from Apacer also supports SD and SPI modes. By using the reliable SLC chip, it not only delivers the features of anti-shock, anti-vibration and low power consumption, but also boasts resistance to extended temperatures (-40°C to 85°C). Available in 256 MB to 8 GB storage capacities, the new SD card can substantially accelerate data transfer, due to its sequential read/write speed reaching up to 20/13 MB per second. It is also worth noting that the card's automatic standby and sleep modes help save power more effectively.

For the just-launched SD card, Apacer also introduces MLC (Multi-Level Cell) flash memory offerings. Boasting the sequential read/write speed to 19/8 MB per second, the product is available in capacities from 4 GB to 32 GB. To ensure that data stay correct, the industrial SD card supports 24-bit ECC function, which minimizes potential errors led by frequent data access to strengthen the system reliability. Also complete with integrated Global Wear leveling and S.M.A.R.T technology, the SD card features a prolonged lifespan as well as safer data storage.

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The new industrial SD card has passed stern reliability tests for temperature, humidity, shock and vibration. Furthermore, post-mass production ORT (on-going reliability testing) is performed to ensure stability.

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